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**Directly heated negative temperature coefficient thermistors –
Part 1: Generic specification**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**DIRECTLY HEATED NEGATIVE TEMPERATURE COEFFICIENT
THERMISTORS –**

Part 1: Generic specification

FOREWORD

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International Standard IEC 60539-1 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment.

This second edition cancels and replaces the first edition published in 2002 and constitutes a minor revision related to tables, figures and references.

The text of this standard is based on the following documents:

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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The QC number that appears on the front cover of the publication is the specification number in the IEC Quality Assessment System for Electronic Components (IECQ).

IEC 60539 consists of the following parts, under the general title *Directly heated negative temperature coefficient thermistors*:

Part 1: Generic specification

Part 2: Sectional specification: Surface mount negative temperature coefficient thermistors

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

DIRECTLY HEATED NEGATIVE TEMPERATURE COEFFICIENT THERMISTORS –

Part 1: Generic specification

1 General

1.1 Scope

This part of IEC 60539 is applicable to directly heated negative temperature coefficient thermistors, typically made from transition metal oxide materials with semiconducting properties.

It establishes standard terms, inspection procedures and methods of test for use in sectional and detail specifications of electronic components for quality assessment or any other purpose.

1.2 Normative references

The following referenced documents are indispensable for the application of this document.. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027-1, *Letter symbols to be used in electrical technology – Part 1: General*

IEC 60050, *International Electrotechnical Vocabulary (IEV)*

IEC 60062, *Marking codes for resistors and capacitors*

IEC 60068-1:1988, *Environmental testing – Part 1: General and guidance*
Amendment 1 (1992)

IEC 60068-2-1:2007, *Environmental testing – Part 2-1: Tests – Tests A: Cold*

IEC 60068-2-2:2007, *Environmental testing – Part 2-2: Tests – Tests B: Dry heat*

IEC 60068-2-6:1995, *Environmental testing – Part 2-6: Tests – Test Fc: Vibration (sinusoidal)*

IEC 60068-2-11:1981, *Environmental testing – Part 2-11: Tests – Test Ka: Salt mist*

IEC 60068-2-14:1984, *Environmental testing – Part 2-14: Tests – Test N: Change of temperature*

Amendment 1 (1986)

IEC 60068-2-17:1994, *Environmental testing – Part 2-17: Tests – Test Q: Sealing*

IEC 60068-2-20:1979, *Environmental testing – Part 2-20: Tests – Test T: Soldering*
Amendment 2 (1987)

IEC 60068-2-21:2006, *Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices*

IEC 60068-2-27:1987, *Environmental testing – Part 2-27: Tests – Test Ea and guidance: Shock*

IEC 60068-2-29:1987, *Environmental testing – Part 2-29: Tests – Test Eb and guidance: Bump*

IEC 60068-2-32:1975, *Environmental testing – Part 2-32: Tests – Test Ed: Free fall*
Amendment 2 (1990)

IEC 60068-2-38:1974, *Environmental testing – Part 2-38: Tests – Test Z/AD: Composite temperature/humidity cyclic test*

IEC 60068-2-45:1980, *Environmental testing – Part 2-45: Tests – Test XA and guidance: Immersion in cleaning solvents*
Amendment 1 (1993)

IEC 60068-2-52:1996, *Environmental testing – Part 2-52: Tests – Test Kb: Salt mist, cyclic (sodium chloride solution)*

IEC 60068-2-54:2006, *Environmental testing – Part 2-54: Tests – Test Ta: Solderability testing of electronic components by the wetting balance method*

IEC 60068-2-58:2004, *Environmental testing – Part 2-58: Tests – Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)*

IEC 60068-2-69:2007, *Environmental testing – Part 2-69: Tests – Test Te: Solderability testing of electronic components for surface mounting devices (SMD) by the wetting balance method*

IEC 60068-2-78:2001, *Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state*

IEC 60294, *Measurement of the dimensions of a cylindrical component having two axial terminations*

IEC 60410, *Sampling plans and procedures for inspection by attributes*

IEC 60617, *Graphical symbols for diagrams*

IEC 60717, *Method for the determination of the space required by capacitors and resistors with unidirectional terminations*

IEC 61249-2-7, *Materials for printed boards and other interconnecting structures – Part 2-7: Reinforced base materials clad and unclad – Epoxide woven E-glass laminated sheet of defined flammability (vertical burning test), copper-clad*

IECQ 001002-3, *IEC Quality Assessment System for Electronic Components (IECQ) – Rules of procedure – Part 3: Approval procedures*

ISO 1000, *SI units and recommendations for the use of their multiples and of certain other units*